

**Notice of References Cited**

Application/Control No.

09/517,163

Applicant(s)/Patent Under  
Reexamination  
HINOUE ET AL.

Examiner

Ryan J Hesseltine

Art Unit

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,193,152 B1	02-2001	Fernando et al.	235/380
	B	US-6,193,153 B1	02-2001	Lambert, Francis	235/380
	C	US-5,978,495 A	11-1999	Thomopoulos et al.	382/124
	D	US-6,185,685 B1	02-2001	Morgan et al.	713/183
	E	US-6,078,848 A	06-2000	Bernstein et al.	700/237
	F	US-6,035,406 A	03-2000	Moussa et al.	713/202
	G	US-6,111,977 A	08-2000	Scott et al.	382/124
	H	US-5,970,146 A	10-1999	McCall et al.	713/194
	I	US-5,768,386 A	06-1998	Yokomoto et al.	713/183
	J	US-6,476,797 B1	11-2002	Kurihara et al.	345/173
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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